# **IGBT - Field Stop II**

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Field Stop II Trench construction, and provides superior performance in demanding switching applications, offering both low on state voltage and minimal switching loss. The IGBT is well suited for motor driver applications. Incorporated into the device is a soft and fast co–packaged free wheeling diode with a low forward voltage.

#### **Features**

- Extremely Efficient Trench with Field Stop Technology
- $T_{Jmax} = 175$ °C
- Soft Fast Reverse Recovery Diode
- Optimized for Low V<sub>CEsat</sub>
- 10 µs Short Circuit Capability
- These are Pb-Free Devices

### **Typical Applications**

- Motor Drive Inverter
- Industrial Switching
- Welding

#### **ABSOLUTE MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Collector-emitter voltage	$V_{CES}$	1200	V
Collector current @ Tc = 25°C @ Tc = 100°C	I <sub>C</sub>	60 30	A
Pulsed collector current, $T_{pulse}$ limited by $T_{Jmax}$ , 10 $\mu s$ Pulse, $V_{GE} = 15 \text{ V}$	I <sub>CM</sub>	120	А
Diode forward current @ Tc = 25°C @ Tc = 100°C	l <sub>F</sub>	60 30	А
Diode pulsed current, T <sub>pulse</sub> limited by T <sub>Jmax</sub>	I <sub>FM</sub>	120	Α
Gate-emitter voltage Transient gate-emitter voltage $(T_{pulse} = 5 \mu s, D < 0.10)$	$V_{\sf GE}$	±20 ±30	V
Power Dissipation @ Tc = 25°C @ Tc = 100°C	P <sub>D</sub>	534 267	W
Short Circuit Withstand Time $V_{GE} = 15 \text{ V}, V_{CE} = 500 \text{ V}, T_J \le 150^{\circ}\text{C}$	T <sub>SC</sub>	10	μs
Operating junction temperature range	TJ	–55 to +175	°C
Storage temperature range	T <sub>stg</sub>	-55 to +175	°C
Lead temperature for soldering, 1/8" from case for 5 seconds	T <sub>SLD</sub>	260	°C

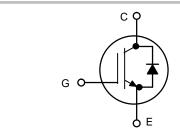
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

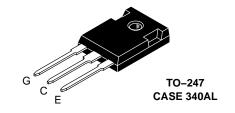


# ON Semiconductor®

http://onsemi.com

30 A, 1200 V V<sub>CEsat</sub> = 1.70 V E<sub>off</sub> = 1.4 mJ





# **MARKING DIAGRAM**



A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

#### **ORDERING INFORMATION**

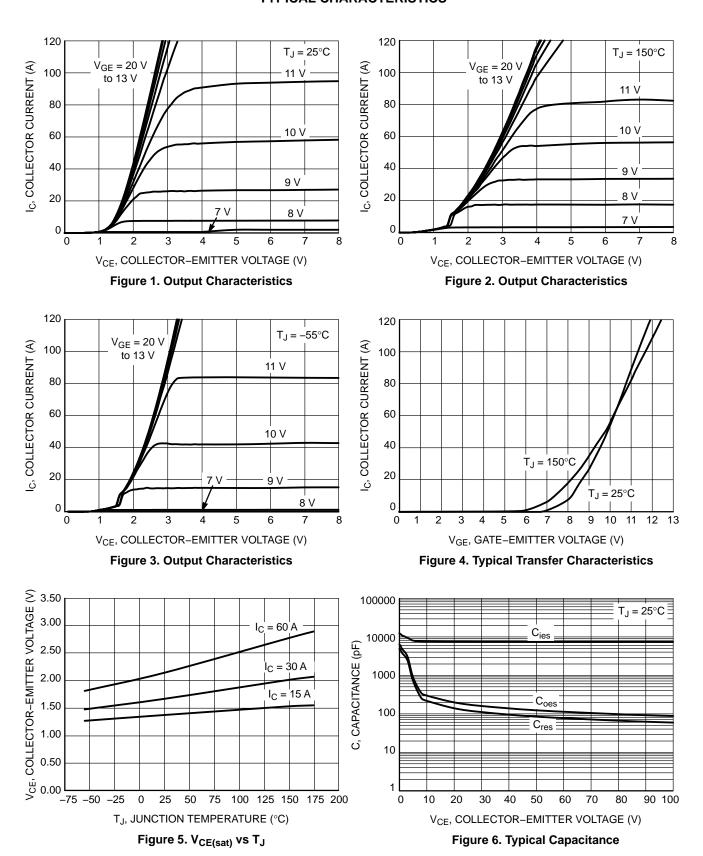
Device	Package	Shipping
NGTB30N120L2WG	TO-247 (Pb-Free)	30 Units / Rail

# THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction–to–case, for IGBT		0.28	°C/W
Thermal resistance junction-to-case, for Diode		0.85	°C/W
Thermal resistance junction-to-ambient		40	°C/W

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
STATIC CHARACTERISTIC	•					
Collector–emitter breakdown voltage, gate–emitter short–circuited	$V_{GE} = 0 \text{ V}, I_{C} = 500 \mu\text{A}$	V <sub>(BR)CES</sub>	1200	_	_	V
Collector–emitter saturation voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 30 A V <sub>GE</sub> = 15 V, I <sub>C</sub> = 30 A, T <sub>J</sub> = 175°C	V <sub>CEsat</sub>	_ _	1.70 2.07	1.90 -	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}, I_{C} = 400 \mu A$	V <sub>GE(th)</sub>	4.5	5.5	6.5	V
Collector-emitter cut-off current, gate- emitter short-circuited	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 1200 V V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 1200 V, T <sub>J =</sub> 175°C	I <sub>CES</sub>	_ _	- -	1.0 2	mA
Gate leakage current, collector–emitter short–circuited	V <sub>GE</sub> = 20 V , V <sub>CE</sub> = 0 V	I <sub>GES</sub>	-	-	200	nA
Input capacitance		C <sub>ies</sub>	_	7500	_	pF
Output capacitance	$V_{CE} = 20 \text{ V}, V_{GE} = 0 \text{ V}, f = 1 \text{ MHz}$	C <sub>oes</sub>	_	200	_	
Reverse transfer capacitance		C <sub>res</sub>	_	140	_	
Gate charge total		Qg	-	310	-	nC
Gate to emitter charge	$V_{CE} = 600 \text{ V}, I_{C} = 30 \text{ A}, V_{GE} = 15 \text{ V}$	Q <sub>ge</sub>	-	61	_	
Gate to collector charge		Q <sub>gc</sub>	-	150	_	
SWITCHING CHARACTERISTIC, INDUC	TIVE LOAD					
Turn-on delay time		t <sub>d(on)</sub>	-	116	_	ns
Rise time	7	t <sub>r</sub>	-	35	-	
Turn-off delay time	T <sub>J</sub> = 25°C	t <sub>d(off)</sub>	-	285	-	
Fall time	$V_{CC} = 600 \text{ V}, I_{C} = 30 \text{ A}$ $R_{r} = 10 \Omega$	t <sub>f</sub>	-	175	-	
Turn-on switching loss	$R_g = 10 \Omega$ $V_{GE} = 0 V / 15 V$	Eon	_	4.4	_	mJ
Turn-off switching loss	7	E <sub>off</sub>	-	1.4	-	
Total switching loss	7	E <sub>ts</sub>	-	5.8	-	
Turn-on delay time		t <sub>d(on)</sub>	-	110	-	ns
Rise time	7	t <sub>r</sub>	-	36	-	
Turn-off delay time	T <sub>J</sub> = 175°C	t <sub>d(off)</sub>	_	300	_	
Fall time	$V_{CC} = 600 \text{ V}, I_{C} = 30 \text{ A}$ $R_{g} = 10 \Omega$	t <sub>f</sub>	-	331	-	
Turn-on switching loss	V <sub>GE</sub> = 0 V/ 15V	E <sub>on</sub>	-	5.5	-	mJ
Turn-off switching loss	1	E <sub>off</sub>	-	2.5	-	
Total switching loss	7	E <sub>ts</sub>	-	8.0	-	
DIODE CHARACTERISTIC						
Forward voltage	V <sub>GE</sub> = 0 V, I <sub>F</sub> = 30 A V <sub>GE</sub> = 0 V, I <sub>F</sub> = 30 A, T <sub>J</sub> = 175°C	V <sub>F</sub>	-	1.50 1.40	1.70 -	V
Reverse recovery time	T <sub>J</sub> = 25°C	t <sub>rr</sub>	-	450	_	ns
Reverse recovery charge	$I_F = 30 \text{ Å}, V_R = 400 \text{ V}$ $di_F/dt = 200 \text{ A/}\mu\text{s}$	Q <sub>rr</sub>	-	7.85	-	μC
Reverse recovery current		I <sub>rrm</sub>	_	32	_	Α



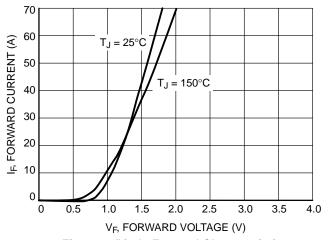


Figure 7. Diode Forward Characteristics

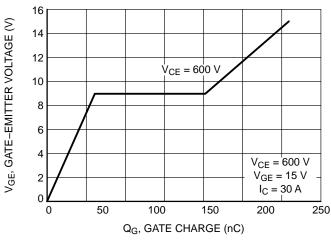


Figure 8. Typical Gate Charge

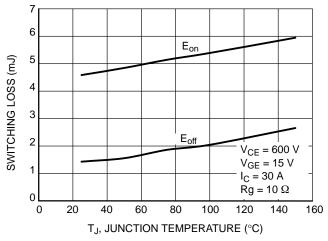


Figure 9. Switching Loss vs. Temperature

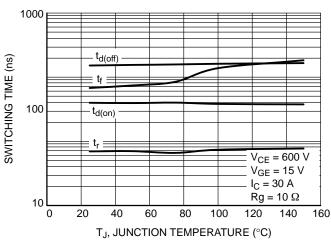


Figure 10. Switching Time vs. Temperature

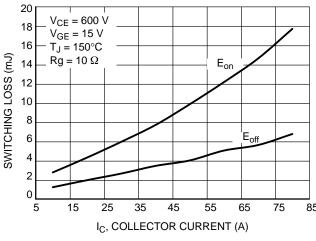


Figure 11. Switching Loss vs. I<sub>C</sub>

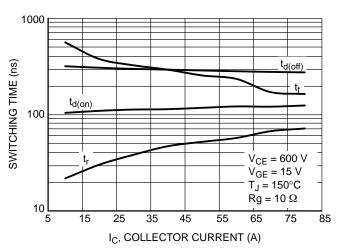


Figure 12. Switching Time vs. I<sub>C</sub>

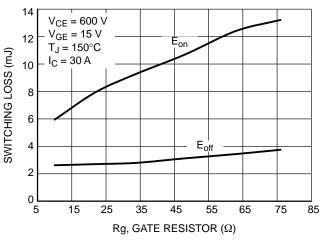


Figure 13. Switching Loss vs. Rg

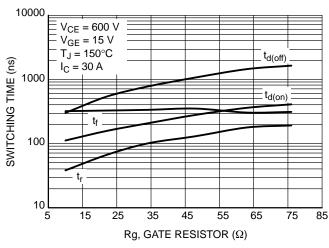


Figure 14. Switching Time vs. Rg

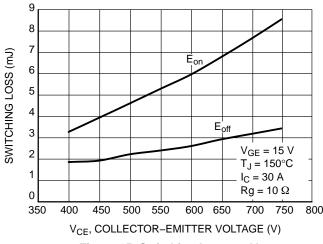


Figure 15. Switching Loss vs. V<sub>CE</sub>

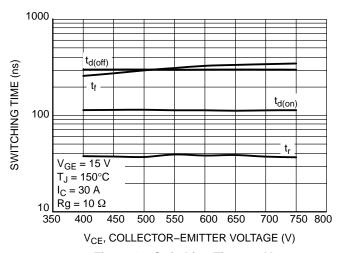


Figure 16. Switching Time vs. V<sub>CE</sub>

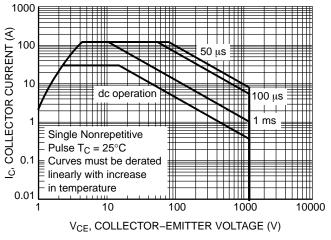


Figure 17. Safe Operating Area

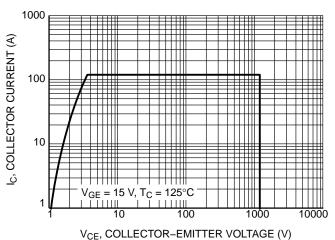


Figure 18. Reverse Bias Safe Operating Area

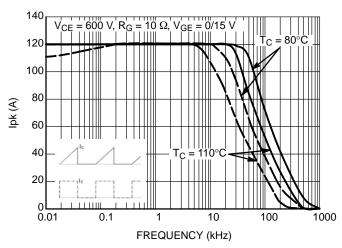


Figure 19. Collector Current vs. Switching Frequency

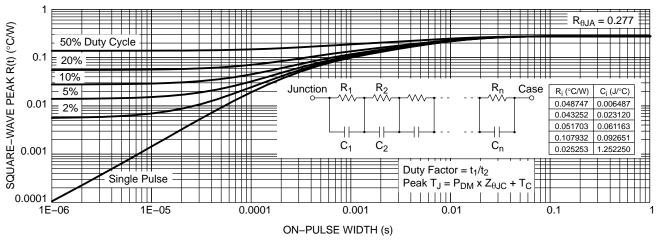


Figure 20. IGBT Transient Thermal Impedance

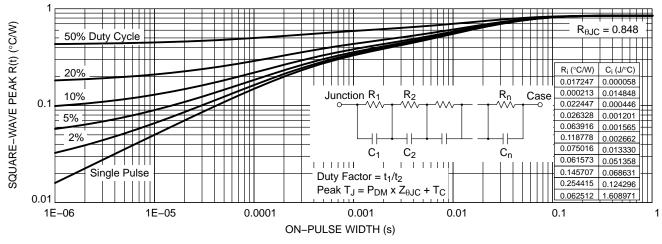
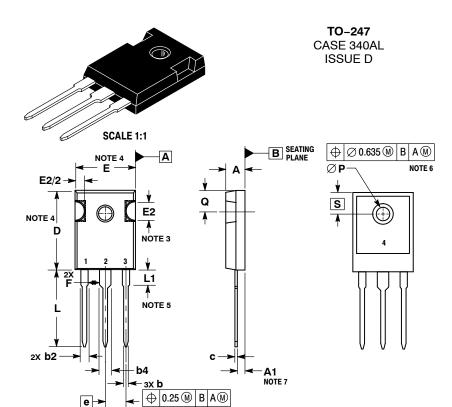


Figure 21. Diode Transient Thermal Impedance



**DATE 17 MAR 2017** 

- NOTES:

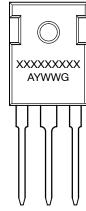
  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETERS.
  3. SLOT REQUIRED, NOTCH MAY BE ROUNDED.

  - DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH.
    MOLD FLASH SHALL NOT EXCEED 0.13 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREME OF THE PLASTIC BODY
  - LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY
- ©P SHALL HAVE A MAXIMUM DRAFT ANGLE OF 1.5° TO THE TOP OF THE PART WITH A MAXIMUM DIAMETER OF 3.91.

  DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED

	MILLIMETERS		
DIM	MIN	MAX	
Α	4.70	5.30	
A1	2.20	2.60	
b	1.07	1.33	
b2	1.65	2.35	
b4	2.60	3.40	
С	0.45	0.68	
D	20.80	21.34	
E	15.50	16.25	
E2	4.32	5.49	
е	5.45 BSC		
F	2.655		
L	19.80	20.80	
L1	3.81	4.32	
P	3.55	3.65	
Q	5.40	6.20	
S	6.15 BSC		

#### **GENERIC MARKING DIAGRAM\***



XXXXX = Specific Device Code Α = Assembly Location

Υ = Year WW = Work Week = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking.

Pb-Free indicator, "G" or microdot " ■", may or may not be present.

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